# 國立交通大學

電機學院光電顯示科技產業研發班

# 碩士論文

四點探針有機薄膜電晶體之氣體感測研究 Study of Gas Sensing Ability on Gated-Four-Probes Organic Thin Film Transistors

# 研究生: 吳文馨

指導教授:冉曉雯 博士

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Study of Gas Sensing Ability on Gated-Four-Probes Organic Thin Film Transistors

研究生:吴文馨 Student:Wen-xin Wu

指導教授:冉曉雯

Advisor : Dr. Hsiao Wen Zan

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#### 四點探針有機薄膜電晶體之氣體感測研究

研究生: 吳文 馨

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#### 國立交通大學

電機學院光電顯示科技產業研發碩士專班

#### 摘 要

在論文中,我們建立一個可定量控制氣體濃度的感測系統,並利用具四 點探針結構的有機薄膜電晶體進行氨氣感測的研究。當氨氣與有機薄膜電晶體反 應時,電晶體的汲極電流會被減少、臨界電壓會往負值增加、但次臨界擺幅幾乎 不受氨氣的影響而改變。而由四點探針結構的量測顯示,電晶體的薄膜電阻與接 觸電阻均隨氨氣濃度的提高而增加。而利用薄膜電阻所推算出來的本質載子遷移 率也會因氨氣濃度的提高而隨之減少。最後則將探討載子遷移率降低、臨界電壓 往負值增加、及幾乎不受氣氣影響的次臨界擺幅,並根據電晶體特性改變的結 果,提出可能的反應機制。

#### Gas sensing ability of Gated-Four-Probes OTFTs study

Student: Wen-xin Wu

Advisor: Dr. Hsiao-Wen Zan

Industrial Technology R & D Master Program of Electrical and Computer Engineering College National Chiao Tung University

#### Abstract

In this thesis, we tried to construct a gas sensing system, in which we can control the gas concentration quantitatively; moreover we also utilized the gated-four-probes organic thin film transistor to investigate the NH<sub>3</sub> gas-sensing experiment. When the NH<sub>3</sub> gas was interacted with OTFT, it was found that the OTFT drain current will be reduced and the threshold voltage will be enlarged toward a negative value. However, the subthreshold swing was not changed significantly by the NH<sub>3</sub> gas. From the analysis of gated-4-probes OTFT, both the film resistance and the contact resistance were increased with the raise of NH<sub>3</sub> concentration. Additionally, the intrinsic field-effect mobility, which was estimated from the film resistance, was also reduced with the raise of the NH<sub>3</sub> concentration.

threshold voltage, and the almost unchanged subthreshold swing were discussed.

A probable mechanism deduced from the change of the OTFT was also summarized and proposed in this study.



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#### **1.1** Introduction of organic thin film transistors (OTFTs)

"Plastic transistors" open the future of flexible displays, smart cards, radio frequency (RF) identification tags, as well as light-emitting diodes (LED) and lasers [1]. Rapid progress in this field has been achieved by improving the material properties and the process techniques .

As for the application of electronics, the organic active layer has attended a mobility of  $1 \text{ cm}^2/\text{Vs}$  and a switching speed of  $10^8$  Hz, which is comparable to amorphous hydrogenated silicon (a-Si:H), as shown in Fig. 2.1 [2]. Since the late 1940s, there has been a lot of research on the development of organic semiconductor [3]. This is because of the large  $\pi$ -conjugation length along the long axis of the molecules and closed  $\pi$ -stacking are the key factors of high carrier mobility [3].

Similar to inorganic semiconductors, organic ones can function as p-type or n-type. However, most reported high-mobility organic semiconductors are p-type material. Among the p-type material, pentacene ( $C_{14}H_{22}$ ), a rod-like aromatic molecule composed of five benzene rings, shows the highest mobility (>1cm<sup>2</sup>/Vs), owning to highly ordered films with proper dielectric properties and growth conditions [4].

#### **1.2** Applications of OTFTs to gas-sensing device

For the next generation of sensor applications on medical diagnostics, food monitoring, and chemical or biological warfare etc.; portable, low cost, and low power-consumption will be important demands. As for these demands, the OTFT should be an important candidate due to its flexibility and its simple fabrication process. Therefore, the studies of organic thin-film transistors (OTFTs) to physical, chemical, and biological sensors will become an important object [5,6,7,8].

Recently, OTFTs are proposed to act as gas sensors. When OTFTs exposed to gaseous species, five parameters: such as the turn-on current  $(I_{on})$ , turn-off current  $(I_{off})$ , threshold-voltage  $(V_{th})$ , field-effect mobility  $(\mu_{eff})$  and subthreshold-swing (S.S.), are used to estimate the gaseous interaction in OTFTs. By this way, a "multi-parameter" gas sensor can be realized by OTFT [9].

#### **1.3** Objective and Motivation

Although the primary gaseous interactions on OTFTs are observed, however, the details of mechanisms are still not well-understood. Unlike the inorganic materials, the bindings between the organic molecules are weak van der Waal force. The stack of organic crystal is loose and contained with voids. Therefore, the gas penetration and gas interaction to the organic devices will be strongly dominated by the organic

semiconductor layer. Besides, the loosely packed organic-film with aromatic compounds will be a good medium for bio-molecules. As a result, to investigate the fundamental of gaseous and biochemical interaction on OTFTs should open a road to high-sensitive organic sensors.

In this study, we try to investigate the effect of sensing ammonia(NH<sub>3</sub>) in pentacene-based OTFTs. By the gated-4-probes OTFTs, the organic film properties and mental-contact effects can be studied separately. The related parameters of TFT, such as pentacene film resistances, intrinsic mobility, threshold voltage, and the subthreshold swing, will also be monitored during the gaseous experiment on OTFTs. Afterwards, we will try to analyze these parameters to characterize the sensing mechanism and propose a potential model.

#### **1.4** Organization of thesis

In chapter 1, we make a brief introduction to the demands on OTFTs and its application on gas sensing. Consequently, in chapter 2, we discuss some basic knowledge about the device operations and the gas sensing properties in OTFTs. The studies of gated-4-probes OTFTs and its analysis are also presented in this part. In chapter 3, the experimental details, such as the devices fabrication, and the connection of gas sensing system are discussed. The effect of sensing ammonia(NH<sub>3</sub>) on OTFT is presented in chapter 4. The transfer characteristics will be shown in these chapters. The related OTFT parameters will also analyze under different gas concentration. In final chapter, we will make a conclusion.



# **CHAPTER 2**

#### 2-1 Transportation mechanisms of organic semiconductor

In the past 20 years, a great deal of progress has been made in improving the field-effect mobilities of OFETs [10,11]. It has also been demonstrated that the properties of charge transport in conjugated molecules are intrinsically correlated with their crystalline structure, where the  $\pi$  delocalized carriers are responsible for the intra-molecular conduction. However, the nature of van der Waals bonding between discreted molecules is thought to be a limitation of the carrier transport, and the transport is usually described by "localized model" [3]. Thus, the charged carrier transport must be described by different models than those in covalently bonded semiconductors.

Recently, two principal types of theoretical models are used to describe the transport in organic semiconductors : "The band-transport model" and "The hopping models". However, band transport may not suit for some disordered organic semiconductors, in which carrier transport is govern by the hopping between localized states. Hopping is assisted by phonons and the mobility increases with temperature. Typically, the mobility is very low, usually much lower than  $1 \text{ cm}^2/\text{V-sec}$ . The boundary between "band transport" and "hopping" is divided by materials mobilities

(~1cm<sup>2</sup>/V-sec) at room-temperature (RT) [12]. Many kinds of polycrystalline organic semiconductors, such as several members of the acene series including pentacene, rubrene, have RT mobility over the boundary [13]. Sometimes, temperature-independent mobility was found in some polycrystalline pentacene devices [14]. Thus, this observation argued that the simply thermal activated hopping process governed the whole carrier transport behaviors in high quality polycrystalline pentacene film, despite that the temperature independent mobility has been observed in exceptional cases [14].

The understanding of cartier transport in single-crystal of organic semiconductors will help us to describe the transport mechanism in polycrystalline organic semiconductors. The coherent band-like transport of delocalized carriers becomes the prevalent transport-mechanism in the single crystal organic semiconductors, such as pentacene, tetracene, under the low-temperature environments. A very high hole mobility has been measured by time-of-flight (TOF) experiments [15]. Thus, the temperature dependence of the carrier mobility was found below 100K and following with a power law of  $\mu \propto T^{-n}$ , n~1 [16], in single crystals of organic semiconductors, consistent with the band-transport model. However, between 100K and 300K, the carrier mobility show a constant value [16], that has been described as the superposition of two independent carrier transport mechanisms. The first mechanism was small molecular polaron (MP). According to this model, the carriers were treated as the heavy, polaron-type, and quasi-particles. It is formed by the interaction of the carriers with intra-molecular vibrations of the local lattice environment, and move coherently via tunneling. In this model, the mobility follows the power law  $\mu_{MP}=aT^{-n}$ . The other involves a small lattice polaron (LP), which moves by thermally activated hopping and exhibits a typical exponential dependence of mobility on temperature :  $\mu_{LP}=bexp[-Ea/kT]$ . The superposition of these two mechanisms could get a good consistence with experimental measurement of temperature-dependence mobility from room temperature to a Kelvin degrees (K) [17].



#### 2-2 Interaction of gases on OTFTs

The OTFTs gas sensing have been several advantages over the chemical resisters. These devices are especially attracted due to their ability to serve as a multi-parameter sensor [9].

Furthermore, Frank Liao indicated that there is the potential for discrimination based on the functional group chemistry of the analytics. The presence of  $\pi$  orbitals or the acidic proton in the acetic acid interacts with the channel of the device to cause trapping and decrease the mobility [7].

#### 2-3 Potential Effects on Gas Sensing in OTFT

#### 2-3.1 Morphology and dimension of Active Layer

Grain boundaries (GBs) play a critical role in OFET sensing. In the repored researches, the control of grain size can be achiered by changing the substrate temperature during deposition. According to the images of transmission electron microscope (TEM), Torsi *et al.* indicate that the response is strong for the low-temperature film, which has more grain boundaries. However, the response is weak for the high-temperature film, which has fewer grain boundaries and shows a more compacted structure [18].

Wang *et al.* also indicate that device channel scale being an important key in sensing process with different mechanisms dominating at different length scales. For a longer channel relative to grain sizes, there are enough grain boundaries inside the channel so that the former effect is dominant and the overall sensing response is the current decreasing. For a shorter channel relative to grain sizes, the latter effect dominates due to very few number of grain boundaries inside channel, which leads to the current increasing by excess charges from the interaction between grains and the analyte [19].

#### **2-3.2 Dipole of the analyte**

For the most analytes, the interactions are attributed to the nature of molecular dipole. For example, the H<sub>2</sub>O will result in the decrease of drain-current [20,21].Although pentacene is highly hydrophobic, H<sub>2</sub>O molecules can easily diffuse into these devices, interact with the traps by and alter the electric field at the grain boundaries. In addition, the presence of polarized molecules is known to decrease the rate of charge transport in organic materials by increasing the amount of energetic disorder through charge–dipole interactions [20].

#### 2-3.3 The Thickness of Active Layer

Yang *et al.* indicate that ultrathin cobalt phthalocyanine(CoPc) transistors of 4 ML compare faster response times, higher base line stabilities, and more sensitive to 50 ML devices [22]. Due to the ultrathin ChemFETs, the holes accumulation extends to the air/CoPc interface; therefore, the surface traps participate in carrier transport and the perturbation of the surface trap energies by the analytes renders the ultrathin ChemFETs more sensitive than the thick ChemFETs [22].

#### 2-3.4 Device area

F. Liao et al. indicated that the device area does not affect the overall sensor

response. Different device areas of (W/L)1 = 500/25 and (W/L)2 = 100/4 both show the same percent change in active current [7].

But in our gas sensing experiments from different dimension of OTFT are show in Fig. 2.1. Different size OTFT will show a slightly different response.

#### 2-4 Gated four-probes OTFTs for resistance measurement

Gated four-probe OTFTs measurements were carried out by using a Keithley 4200-SCS semiconductor parameter analyzer. In the four-terminal measurements, as show in Fig. 2-2(a) the voltage  $V_1$  and  $V_2$  between the source and drain electrodes. The probing current of voltage probes is about 10<sup>-13</sup>A, which is lower than the drain-current. In Fig. 2-2(b), an idealized depiction of the potential distribution in the 411111 channel region, when OTFT is operated in linear region and above threshold condition  $|V_{DS}| < |V_{GS} - V_T|$ . Where  $V_T$  is the threshold voltage,  $V_{GS}$  is the gate-source voltage, and  $V_{DS}$  is the drain-source voltage. In Fig. 2-3, the voltage difference between the voltage probes  $V_1 - V_2$  from four-terminal measurement. This voltage difference varies linearly with increasing  $V_{DS}$  over a limited range of  $V_{DS}$ and shows almost no gate voltage dependence. Such linear dependence on  $V_{\rm DS}$  is expected if the device behaves as predicted by simple FET theory. At a large  $V_{DS}$ , the potential difference between the voltage probes is nearly constant and independent of  $V_{\rm DS}$ . This behavior is also predicted from simple FET theory for the saturation region.

By measuring,  $V_1$  and  $V_2$ , a linear extrapolation of the potential profile to each contact was performed. The potential drops at the source electrode ( $\Delta V_S$ )  $\cdot$  drain electrode ( $\Delta V_D$ ) and organic film ( $\Delta V_{Film}$ ), were calculated according to the following equations:

$$\Delta V_{s} = \left[ V_{2} - \frac{(V_{1} - V_{2})}{(L_{2} - L_{1})} (L - L_{2}) \right] - V_{s}$$
(1)

$$\Delta V_D = V_D - \left[ V_2 + \frac{(V_1 - V_2)}{(L_2 - L_1)} L_2 \right]$$
(2)

$$\Delta V_{Film} = \frac{(V_1 - V_2)}{(L_2 - L_1)} L$$
(3)

where  $V_s$ ,  $V_D$ ,  $V_1$ , and  $V_2$  are the voltages at the source, drain, and two potential probes, respectively.  $L_1$  is drain electrode to the first potential probe.  $L_2$  is drain electrode to the second potential probe. L is the distances from the drain electrode to source electrode. Where  $\Delta V_{Film}$  is the actual voltage drop across the film.

With the measured total current flowing through the device and the potential drops across the film and contacts, the resistance of the source contact, drain contact, and the film can be calculated using Ohm's Law, when devices operation in linear region.

$$R_{\rm s} = \frac{\Delta V_{\rm s}}{I_{\rm D}} \tag{4}$$

$$R_D = \frac{\Delta V_D}{I_D}$$
(5)

$$R_F = \frac{\Delta V_F}{I_D}$$



(6)

# **CHAPTER 3**

#### **3.1 Device Fabrication**

#### **3.1-1 Preparation of Substrates**

In this study, the OTFT devices we used are top-contact structures. A p-type, single crystal silicon wafer (100) was used as the substrate and the gate electrode. After RCA cleaning, a 1000Å thermally-grown SiO<sub>2</sub> layer was deposited on wafer by furnace. After the SiO<sub>2</sub> deposition, we removed the SiO<sub>2</sub> layer from the wafer of unpolished-side. The etching-solution we used is buffered oxide etching (B.O.E.) solution (NH4F : HF=6 : 1). Hence, the wafer of unpolished-side without SiO<sub>2</sub> layer can serve as a gate-electrode. Finally, the substrate was cleaned in ultrasonic tank by the sequence of: de-ionic water (5 minutes), acetone (1 minutes), and de-ionic water (5 minutes).

#### 3.1-2 Spin-coated PMMA on SiO<sub>2</sub>

After substrate cleaning, we spun the solution-based Polymethylmethacrylate (PMMA) unto the substrate. The content of solution-based PMMA is a mix of PMMA and anisole with a concentration of 11.81wt%.

Consequently, we try to remove the residual solvent, by baking the substrate on hot-plate at 90°C about 30 minutes.

#### **3.1-3** Growth of Thin Film and Electrodes

Pentacene powder was purchased from SIGMA-ALDRICH. Without any purification, pentacene powder was sublimated and deposited on substrate as an active layer under a pressure below  $1.5 \times 10^{-6}$  torr. The substrate was kept at  $26^{\circ}$ C. The deposition rate was about 0.5Å/s and the pentacene-film thickness was about 1000 Å. All the deposition parameters are monitored by a quartz crystal microbalance (QCM) during the deposition process. In the end, a 1000Å Au layer was used as the source and drain pad, which is deposited at a rate of  $1\sim2$  Å/sec under  $3\times 10^{-6}$  torr. The channel width (W) and length (L) defined by shadow-mask was 800µm and 1200µm, respectively.

#### **3.2 Gas-Sensing system**

As shown in Fig. 3.1, the gas-sensing system consists of three major parts: a gaseous analyte controller, a gas-proof chamber, and a semiconductor parameter analyzer. In Fig. 3.2(a), (b), and (c), we show the mass flow controller, the power supply, and pressure gauge, respectively. The gaseous analyte was introduced into

the gas-proof chamber and controlled by the mass flow controllers (MFC; 5850E, Brooks Instrument). The pressure inside the gas-proof chamber was monitored by vacuum gauge (PC-615, PROTEC). The total volume of the gas-proof chamber is about 52.8 liter. Fig. 3.3 is the top-view image of gas-sensing system. The system was equipped with five Kelvin-probes and positioners. The probes were connected to the semiconductor analyzer (Keithley 4200-SCS) via tri-axial cables. The bottom pipe and the upper pipe served as the gas-inlet and gas-exhaust, respectively. After mounting a metal cap with transparent window, as shown in Fig. 3.4, the gas-proof chamber can be pumped down to less than 1 torr. Consequently, we introduced the pure nitrogen (N<sub>2</sub>) gas into the gas-proof chamber. Thus, all the gaseous-sensing experiments can be processed in a low-humidity and low-oxygen ambiance. All the experiments were also be operated at a pressure about 760 torr.

### **CHAPTER 4**

#### **4-1 Characteristics of Gated-Four-Probes OTFTs**

In order to improve the OTFTs performance and pentacene crystallization, the SiO2 surface is spin-coated with an ultra-thin PMMA layer. In Fig. 4-1(a) and (b), we show the atomic force microscope (AFM) images of SiO<sub>2</sub> dielectric and PMMA-coated SiO<sub>2</sub> dielectric. As we can observe, the surface roughness of SiO<sub>2</sub> and PMMA-coated SiO<sub>2</sub> is about 0.21 *nm* and 0.20 *nm*, respectively. The PMMA layer will not affect the surface roughness significantly. From the capacitance measurements, the total capacitance value is reduced from 34 nF/cm<sup>2</sup> to 23.4 *nF/cm*<sup>2</sup>. By the serious-capacitance formula:

$$\frac{1}{C_{total}} = \frac{1}{C_{SiO_2}} + \frac{1}{C_{PMMA}}$$
$$C_i = \frac{\varepsilon_0 \cdot \varepsilon_i}{t_i}$$

 $C_{total}$ ,  $C_{SiO_2}$ , and  $C_{PMMA}$  is the total capacitance, the SiO<sub>2</sub> capacitance, and the PMMA capacitance, respectively.  $\varepsilon_i$  is the permittivity in vacuum.  $\varepsilon_i$  and  $t_i$ indicates the relative dielectric constant and the dielectric thickness, respectively. By taking the  $\varepsilon_{SiO_2} = 3.9$ ,  $t_{SiO_2} = 100nm$ , and  $\varepsilon_{PMMA} = 3.5$ , the estimated thickness of PMMA layer is about 41 nm. The pentacene AFM image on PMMA-coated SiO<sub>2</sub> layer is also show in Fig. 4-1(c), an average grain-size and roughness about  $1\sim 2 \ \mu m$ and 15.1 nm can be observed in the figure, respectively. After the source, drain, and voltage-probing electrodes are deposited on pentacene film, we measured the transfer characteristics of the gated-4-probes OTFT. The drain-current is plotted as a function of gate-voltage in Fig. 4-2. The devices shows an on/off current ratio about 5 order and a low hysteresis when the devices is operated above the threshold voltage.

To obtain correct parameters from gated-4-probes OTFT, it is important to choose the range of operation voltage. It is well known that four-terminal electrical measurement is based on the Ohm's Law. The voltage-drop will be linearly changed with the increase of drain-voltage. However, the linear-dependence is not always As show in Fig. 4-3 (a), the voltage difference between expected at any voltage bias. 400000 potential-probes is plotted as a function of drain voltage, respectively. The voltage difference  $(V_2 - V_1)$ , will not linearly increase with drain-voltage  $(V_D)$  and show almost no gate-voltage  $(V_G)$  dependence when the  $V_D$  is less than -4 V. The result can be explained by the output characteristics  $(I_D - V_D)$  in Fig. 4-3(b). When the  $V_D$  increases, the  $I_D - V_D$  curve is converted from a linear-relation to a saturated-relation. It is clear that when the gated-4-probes OTFT is operated at a small  $V_D$  e.g. less than -5 V, the extracted parameters will be correct. Hence, in the consequent experiment, the  $V_D$  is fixed at -3 V.

#### 4-2 Effects of ammonia (NH<sub>3</sub>) on Gated four-probe OTFTs

Before the measurement, the gas-sensing chamber is pumped-down to less than 1 torr and vented to 760 *torr* by the high-purity nitrogen (N<sub>2</sub>) gas. Initially, we measured the gated-4-probe OTFT in the nitrogen ambiance. As shown in Fig. 4-4(a) and 4-4(b), the transfer characteristic is plotted in semi-log scale and linear-scale. Under the nitrogen ambiance, the device show a mobility about 0.37  $cm^2/V$ -sec, an on/off current ratio more than 5 orders, a threshold voltage about -24 V, and a subthreshold swing about 0.97 *decadeV*. When the NH<sub>3</sub> is introduced into the chamber, the drain-current  $(T_p)$  will reduced with the increase of the NH<sub>3</sub> concentration. Interestingly, the threshold voltage will also shift more negatively. The on/off current ratio and the subthreshold swing will not be changed significantly with the increase of the NH<sub>3</sub> concentration.

To further study the effects of NH<sub>3</sub> gas on OTFT devices, we try to estimate the contact resistance and pentacene resistance by the gated-4-probe OTFT, respectively. From potential-probes on channel, the voltage-drops at the source electrode ( $\Delta V_s$ ), drain electrode ( $\Delta V_D$ ), and within the pentacene film ( $\Delta V_{film}$ ) can be estimated by:

$$\Delta V_{S} = \left[ V_{2} - \frac{(V_{1} - V_{2})}{(L_{2} - L_{1})} (L - L_{2}) \right] - V_{S}$$

$$\Delta V_D = V_D - \left[ V_2 + \frac{(V_1 - V_2)}{(L_2 - L_1)} L_2 \right]$$
$$\Delta V_{Film} = \frac{(V_1 - V_2)}{(L_2 - L_1)} L$$

 $V_1$  and  $V_2$  is the voltage measured from the first potential probe (near the drain electrode) and second potential probe (near the source electrode), respectively.  $L_1$ and  $L_2$  is the distance from the first potential probe to drain electrode and the second potential probe to source electrode. L is the channel length.  $V_D$  and  $V_S$  is the drain voltage and source voltage, respectively. The total contact resistance ( $R_{cont}$ ) and film resistance ( $R_{film}$ ) can also be estimate by:



As shown in Fig. 4-5, the  $R_{cont}$  and the  $R_{film}$  is plotted as a function of gate-voltage minus threshold-voltage  $(V_G - V_{th})$ , respectively. When the NH<sub>3</sub> gas is introduce into the gas-sensing chamber, both the  $R_{cont}$  and the  $R_{film}$  will increase. The  $R_{cont}$ and  $R_{film}$  is further plotted as a function of injected NH<sub>3</sub> in Fig 4-6(a). When the injected NH<sub>3</sub> is increased to 0.59 *ppm*, the  $R_{cont}$  will approach a maximum value about  $1.0 \times 10^6 \Omega$ , which is smaller than the value of  $R_{film}$  around  $8.3 \times 10^6 \Omega$ . The Fig. 4-6(b) shows the percentage (%) of  $R_{cont}$  and  $R_{film}$  versus injected NH<sub>3</sub>, respectively. It is clear that the percentage (%) of  $R_{film}$  is as high as about 90%

during the NH<sub>3</sub> gaseous experiment. Thus, the OTFT characteristics should be mainly dominated by the pentacene film properties rather than the contact properties.

Since the pentacene film properties will dominate the OTFT characteristics during the NH<sub>3</sub> gaseous experiment, we try to observe the intrinsic variation of field-effect mobility. In gated-4-probes measurement, the contact-corrected field-effect mobility  $(\mu_{eff})$  can be extracted by

$$\mu_{eff} = \frac{1}{C_{total}} \cdot \frac{\partial \sigma}{\partial V_G}$$
$$\sigma = \frac{I_D}{V_2 - V_1} \cdot \frac{L'}{W}$$

where  $C_{total}$  is the total capacitance of OTFT,  $\sigma$  is the conductivity,  $V_1$  and  $V_2$  is the voltage measured from the first potential probe (near the drain electrode) and second potential probe (near the source electrode), L' is the distance between two potential probes, and W is the channel width. The extracted contact-corrected field-effect mobility is plotted as a function of injected NH<sub>3</sub> gas at a  $V_D = -3V$  and  $V_G - V_{th} = -25V$  in Fig. 4-7. When the NH<sub>3</sub> concentration is increased, the contact-corrected field-effect mobility will decrease monochromatically from 0.39  $cm^2/V$ -sec to 0.34  $cm^2/V$ -sec. The threshold voltage shift ( $\Delta V_{th}$ ) and the subthreshold swing (*S.S.*) is also plotted as a function of NH<sub>3</sub> concentration in Fig. 4-8(a) and Fig. 4-8(b), respectively. The threshold voltage will shift toward more negatively with the increase of NH<sub>3</sub> concentration. However, the subthreshold swing is kept at an averaged value around  $0.94\pm0.03$  *V/decade* and seems not be effected by the NH<sub>3</sub> dramatically, even when the NH<sub>3</sub> concentration is approached to a concentration of 0.59 *ppm*.

In none-crystalline semiconductor, the carrier field-effect mobility will be influenced by the grain-boundary (GB) potential barrier height  $q\phi_b$ . The mostly proposed GB barrier height model is described by

$$\mu_{eff} = \mu_{ig} \cdot \exp(-\frac{q\phi_b}{kT})$$
$$\phi_b = \frac{qN_t^2 d}{8\varepsilon_s C_{ox}(V_G - V_{th})}$$

Where  $\mu_{ig}$  is intra-grain carrier mobility, q is elementary electron,  $N_i$  is the grain-boundary trap density, d is the thickness of semiconductor,  $\varepsilon_s$  is the semiconductor dielectric constant,  $C_{ox}$  is the gate insulator capacitance, k is the Boltzmann's constant, and T is the absolute temperature. According to the equation, the estimated GB barrier height and trap density is plotted as a function of NH<sub>3</sub> concentration in Fig. 4-9. As we can observe, the GB barrier height will slightly increase from 82.8 meV to 87.2 meV and the corresponding trap density will increase from  $1.3 \times 10^{11}$  to  $1.4 \times 10^{11}$  cm<sup>-2</sup>, when the NH<sub>3</sub> is introduced into the chamber. Base on the experimental result, the reduction of drain current should be dominated by the slightly increased GB barrier. When the NH<sub>3</sub> molecular is introduced, the molecular will be adsorbed by the pentacene film. The polycrystalline pentacene

with a lot of GBs will serve additional sites to interact with NH<sub>3</sub> molecular. Hence, the absorbed NH<sub>3</sub> molecular on the GBs will increase the barrier height and acts as trapping sites.

It has also been reported that the amino function-groups will shift the OTFT threshold voltage and the turn-on voltage [24]. In our experiment, as shown in Fig. 4-8(a), an increased (negatively shift) threshold voltage implies the concentration of mobile holes in the pentacene film will be reduced. The NH<sub>3</sub> molecular shows the character of "hole-withdrawing" when it interacts with the pentacene film. It should attribute to the NH<sub>3</sub> molecular is polarized, which probably acts as a positive charged sites when it interacts with pentacene film. On the other hand, the interface trap density between the pentacene and dielectric can also be extracted from the subthreshold swing by

$$N_{ss} = \left[\frac{S \cdot \log(e)}{kT/q} - 1\right] \cdot \frac{C_i}{q}$$

where S is the subtheshold swing; C<sub>i</sub> is the capacitance per unit area; k is Boltzmann's constant, and T is the absolute temperature. In Fig. 4-10, by substituting C<sub>i</sub> =23.4  $nf/cm^2$  and S= 0.94±0.03V/decade yields an averaged interface trap density in the devices of  $2.1 \times 10^{12}$  cm<sup>-2</sup>eV<sup>-1</sup>. The interface trap density will not be influenced significantly after the pentacene film interacts with the NH<sub>3</sub> molecular.

# **CHAPTER 5**

# Conclusion

In summary, we constructed a gas-sensing system and investigated the interaction of pentacene film to NH3 gas via the gated-4-probes OTFT. In our observation, when NH<sub>3</sub> gas interacted with the OTFT, both the contact resistance and the pentacene film resistance are increased, which resulted in the reduction of drain-current. The threshold voltage is also shifted negatively to a larger value; however, the subthreshold swing was almost unchanged. According to our estimation, the increase of pentacene-film resistance will reduce the intrinsic field-effect mobility. It should be attributed to the interaction of NH<sub>3</sub> gas and pentacen film will create additional traps in the pentacene grain, which will increase of grain boundary (GB) barrier height. On the other hand, based on the negatively increased threshold voltage and the almost unchanged subthreshold swing, the NH<sub>3</sub> shows a character of "hole withdrawing" in pentacene film but do not influence the distribution of interface trap significantly. We suggest that the strong interaction between NH<sub>3</sub> gas and OTFT may be connected to the highly polarized NH<sub>3</sub> molecule, but further work is needed to determine the detail of related mechanism.

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**Figure 1.1** The applications of plastic transistors: (a) flexible displays, (b) smart cards, (c) RFID tags, and (d) the nervous system of robot skin. [Adapted from <a href="http://tech.sina.com.en/digi/2006-04-20/1204911539.shtml">http://tech.sina.com.en/digi/2006-04-20/1204911539.shtml</a>]



**Figure 1.2** Evolution of hole mobility for the most common p-type organic semiconductors [2].



Figure 2.1 The degration of field-effect mobility from two OTFTs with different

channel dimensions.



**Figure 2-2.** (a) Top view of a gated-four-probes OTFT. (b) The potential distribution in an OTFT channel region. The potential drop of the organic film is assumed to be

linear. But the potential different at the source and drain electrodes are also given.



a function of drain voltage at different gate voltage.

a ann









(c)



Figure 3.2 (a) The mass flow controller of gas sensing system. (b) The power supply of mass flow controller. (c) The pressure gauge of gas sensing system.



Figure 3.3 Top-view image of gas-sensing system.



Figure 3.4 Top-view image of gas-sensing system mounting a metal cap with transparent window.



**Figure 4.1** The atomic force microscope (AFM) images of (a)  $SiO_2$  dielectric. (b) PMMA-coated  $SiO_2$  dielectric. (c) pentacene AFM image on PMMA-coated  $SiO_2$  layer.



**Figure 4.2** The drain-current is plotted as a function of gate-voltage. (a) Device is operated at linear region. (b) Device is operated at saturation region.



**(a)** 



**Figure 4.3 (a)** The voltage difference between potential-probes is plotted as a function of drain voltage, at different gate voltagde respectively. (b) The output characteristics  $(I_D - V_D)$  show that when  $V_D$  increases, the  $I_D - V_D$  curve will be converted from a linear-relation to a saturated-relation.



Figure 4.4 The transfer characteristic of gate-four-probes OTFT is plotted in (a) semi-log scale and (b) linear-scale, respectively.



**Figure. 4-5** The total contact resistance ( $R_{cont}$ ) and the pentacene film resistance ( $R_{film}$ ) is plotted as a function of gate-voltage minus threshold-voltage ( $V_G - V_{th}$ ), respectively.







Figure. 4-6 (a) The  $R_{cont}$  and  $R_{film}$  is further plotted as a function of NH<sub>3</sub> concentration. (b) The percentage (%) of  $R_{cont}$  and  $R_{film}$  versus NH<sub>3</sub> concentration.

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Figure. 4-7 The extracted ontrinsic field-effect mobility is plotted as a function of NH<sub>3</sub> concentration gas at a  $V_D = -3V$  and  $V_G - V_{th} = -25V$ .







**Figure. 4-8** (a) The threshold voltage shift  $(\Delta V_{th})$  and (b) the subthreshold swing (S.S.) is also plotted as a function of NH<sub>3</sub> concentration, respectively.



Figure. 4-9 The estimated GB barrier height and GB trap density is plotted as a function of NH<sub>3</sub> concentration.





**Figure. 4-10** The subthreshold swing and interface trap density will not be influenced significantly after the pentacene film interacts with the NH<sub>3</sub> molecular.



# 簡 歷

姓名: 吳文馨

出生日期: 中華民國七十一年十月二十五日(1982.10.25)

地址:屏東縣潮州鎮朝昇路 372 巷1號

學歷:

南台科技大學電機系學士

(2001.09-2005.06)

國立交通大學電機學院 光電顯示科技產業研發班

(2005.09-2007.08)

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四點探針有機薄膜電晶體之氣體感測研究

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Organic Thin Film Transistors.